

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/570,875 MAMBA ET AL.	
		Examiner NAY TUN	Art Unit 4153	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,790,961 A	08-1998	Ingram et al.	455/574
*	B	US-6,489,883 B1	12-2002	Iiyama et al.	340/5.1
*	C	US-2003/0141989 A1	07-2003	Arisawa et al.	340/870.01
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2002057617 A	02-2002	Japan	Matsushita et al.	H04B 7/26
*	O	JP 2000090220 A	03-2000	Japan	DAIKYO et al.	G06K 19/07
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.